# 2-Bit Dual-Supply Non-Inverting Level Translator

The NLSV2T244 is a 2-bit configurable dual-supply voltage level translator. The input  $A_n$  and output  $B_n$  ports are designed to track two different power supply rails,  $V_{CCA}$  and  $V_{CCB}$  respectively. Both supply rails are configurable from 0.9 V to 4.5 V allowing universal low-voltage translation from the input  $A_n$  to the output  $B_n$  port.

#### **Features**

- Wide V<sub>CCA</sub> and V<sub>CCB</sub> Operating Range: 0.9 V to 4.5 V
- High-Speed w/ Balanced Propagation Delay
- Inputs and Outputs have OVT Protection to 4.5 V
- Non-preferential V<sub>CCA</sub> and V<sub>CCB</sub> Sequencing
- Outputs at 3-State until Active V<sub>CC</sub> is Reached
- Power-Off Protection
- Outputs Switch to 3-State with V<sub>CCB</sub> at GND
- Small Packaging: UDFN8, SO-8, Micro8
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

#### **Typical Applications**

• Mobile Phones, PDAs, Other Portable Devices

#### **Important Information**

• ESD Protection for All Pins: HBM (Human Body Model) > 5000 V



# ON Semiconductor®

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#### MARKING DIAGRAMS



#### UDFN8 MU SUFFIX CASE 517AJ



UP = Specific Device CodeM = Date Code= Pb-Free Package



SO-8 D SUFFIX CASE 751



A = Assembly Location
L = Wafer Lot
Y = Year
W = Work Week

■ = Pb–Free Package



#### Micro8 DM SUFFIX CASE 846A



A = Assembly Location

/ = Year

W = Work Week
■ = Pb–Free Package

# **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NLSV2T244MUTAG	UDFN8 (Pb-Free)	3000 / Tape & Reel
NLSV2T244DR2G	SO-8 (Pb-Free)	2500 / Tape & Reel
NLSV2T244DMR2G	Micro8 (Pb-Free)	4000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

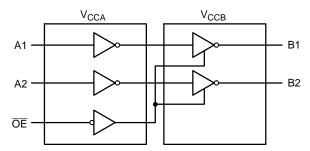
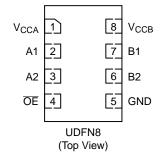
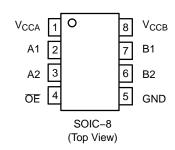
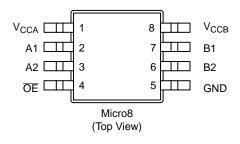


Figure 1. Logic Diagram

# **PIN ASSIGNMENTS**







# **PIN ASSIGNMENT**

PIN	FUNCTION
V <sub>CCA</sub>	Input Port DC Power Supply
V <sub>CCB</sub>	Output Port DC Power Supply
GND	Ground
A <sub>n</sub>	Input Port
B <sub>n</sub>	Output Port
ŌĒ	Output Enable

# **TRUTH TABLE**

In	Outputs	
ŌĒ	A <sub>n</sub>	B <sub>n</sub>
L	L	L
L	Н	Н
Н	Х	3-State

# **MAXIMUM RATINGS**

Symbol	Rating		Value	Condition	Unit
V <sub>CCA</sub> , V <sub>CCB</sub>	DC Supply Voltage		-0.5 to +5.5		V
VI	DC Input Voltage	A <sub>n</sub>	-0.5 to +5.5		V
V <sub>C</sub>	Control Input	OE	-0.5 to +5.5		V
Vo	DC Output Voltage (Power Down)	B <sub>n</sub>	-0.5 to +5.5	$V_{CCA} = V_{CCB} = 0$	V
	(Active Mode)	B <sub>n</sub>	-0.5 to +5.5		V
	(Tri-State Mode)	B <sub>n</sub>	-0.5 to +5.5		V
I <sub>IK</sub>	DC Input Diode Current		-20	V <sub>I</sub> < GND	mA
lok	DC Output Diode Current		-50	V <sub>O</sub> < GND	mA
Io	DC Output Source/Sink Current		±50		mA
I <sub>CCA</sub> , I <sub>CCB</sub>	DC Supply Current Per Supply Pin		±100		mA
I <sub>GND</sub>	DC Ground Current per Ground Pin		±100		mA
T <sub>STG</sub>	Storage Temperature		-65 to +150		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Unit		
V <sub>CCA</sub> , V <sub>CCB</sub>	Positive DC Supply Voltage	0.9	4.5	V		
VI	Bus Input Voltage	GND	4.5	V		
$V_{C}$	Control Input	ŌĒ	GND	4.5	V	
$V_{IO}$	Bus Output Voltage (Power Down Mode)	B <sub>n</sub>	GND	4.5	V	
	(Active Mode)	B <sub>n</sub>	GND	V <sub>CCB</sub>	V	
	(Tri–State Mode)	B <sub>n</sub>	GND	4.5	V	
$T_A$	Operating Temperature Range	-40	+85	°C		
Δt / ΔV	Input Transition Rise or Rate V <sub>I</sub> , from 30% to 70% of V <sub>CC</sub> ; V <sub>CC</sub> = $3.3 \text{ V} \pm 0.3 \text{ V}$	Input Transition Rise or Rate				

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

# DC ELECTRICAL CHARACTERISTICS

					−40°C to	o +85°C	
Symbol	Parameter	Test Conditions	V <sub>CCA</sub> (V)	V <sub>CCB</sub> (V)	Min	Max	Unit
V <sub>IH</sub>	Input HIGH Voltage		3.6 – 4.5	0.9 – 4.5	2.2	_	V
	(An, $\overline{\text{OE}}$ )		2.7 – 3.6	1	2.0	-	1
			2.3 – 2.7	1	1.6	_	
			1.4 – 2.3	1	0.65 * V <sub>CCA</sub>	_	1
			0.9 – 1.4		0.9 * V <sub>CCA</sub>	_	
V <sub>IL</sub>	Input LOW Voltage		3.6 – 4.5	0.9 – 4.5	-	0.8	V
	(An, $\overline{OE}$ )		2.7 – 3.6		_	0.8	
			2.3 – 2.7		-	0.7	
			1.4 – 2.3		_	0.35 * V <sub>CCA</sub>	
			0.9 – 1.4		_	0.1 * V <sub>CCA</sub>	
V <sub>OH</sub>	Output HIGH Voltage	$I_{OH} = -100 \mu A; V_I = V_{IH}$	0.9 – 4.5	0.9 – 4.5	V <sub>CCB</sub> - 0.2	-	V
		$I_{OH} = -0.5 \text{ mA}; V_I = V_{IH}$	0.9	0.9	0.75 * V <sub>CCB</sub>	_	
		$I_{OH} = -2 \text{ mA}; V_I = V_{IH}$	1.4	1.4	1.05	_	
		$I_{OH} = -6 \text{ mA}; V_I = V_{IH}$	1.65	1.65	1.25	_	
			2.3	2.3	2.0	_	
		$I_{OH} = -12 \text{ mA}; V_I = V_{IH}$	2.3	2.3	1.8	_	
			2.7	2.7	2.2	_	
		$I_{OH} = -18 \text{ mA}; V_I = V_{IH}$	2.3	2.3	1.7	_	
			3.0	3.0	2.4	-	
		$I_{OH} = -24 \text{ mA}; V_I = V_{IH}$	3.0	3.0	2.2	_	
$V_{OL}$	Output LOW Voltage	$I_{OL} = 100 \mu A; V_I = V_{IL}$	0.9 - 4.5	0.9 – 4.5	-	0.2	V
		$I_{OL} = 0.5 \text{ mA}; V_I = V_{IL}$	1.1	1.1	-	0.3	
		$I_{OL} = 2 \text{ mA}; V_I = V_{IL}$	1.4	1.4	-	0.35	
		$I_{OL} = 6 \text{ mA}; V_I = V_{IL}$	1.65	1.65	_	0.3	
		$I_{OL} = 12 \text{ mA}; V_I = V_{IL}$	2.3	2.3	_	0.4	
			2.7	2.7	-	0.4	
		$I_{OL} = 18 \text{ mA}; V_I = V_{IL}$	2.3	2.3	-	0.6	
			3.0	3.0	-	0.4	
		$I_{OL}$ = 24 mA; $V_I$ = $V_{IL}$	3.0	3.0	-	0.55	
l <sub>l</sub>	Input Leakage Current	$V_I = V_{CCA}$ or GND	0.9 - 4.5	0.9 – 4.5	-1.0	1.0	μΑ
l <sub>OFF</sub>	Power-Off Leakage Current	OE = 0 V	0 0.9 – 4.5	0.9 – 4.5 0	-1.0 -1.0	1.0 1.0	μΑ
I <sub>CCA</sub>	Quiescent Supply Current	$V_I = V_{CCA}$ or GND; $I_O = 0$ , $V_{CCA} = V_{CCB}$	0.9 – 4.5	0.9 – 4.5	_	1.0	μΑ
I <sub>CCB</sub>	Quiescent Supply Current	$V_I = V_{CCA}$ or GND; $I_O = 0$ , $V_{CCA} = V_{CCB}$	0.9 – 4.5	0.9 – 4.5	-	1.0	μΑ
CA + I <sub>CCB</sub>	Quiescent Supply Current	$V_I = V_{CCA}$ or GND; $I_O = 0$ , $V_{CCA} = V_{CCB}$	0.9 – 4.5	0.9 – 4.5	-	2.0	μΑ
$\Delta I_{CCA}$	Increase in I <sub>CC</sub> per Input Voltage, Other Inputs at V <sub>CCA</sub> or GND	$V_I = V_{CCA} - 0.6 \text{ V};$ $V_I = V_{CCA} \text{ or GND}$	4.5 3.6	4.5 3.6	-	10 5.0	μΑ
$\Delta I_{CCB}$	Increase in I <sub>CC</sub> per Input Voltage,	$V_I = V_{CCA} - 0.6 V;$	4.5 3.6	4.5 3.6	-	10	μΑ
CCB	Other Inputs at V <sub>CCA</sub> or GND	$V_I = V_{CCA}$ or GND	3.0	3.0		5.0	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TOTAL STATIC POWER CONSUMPTION ( $I_{CCA} + I_{CCB}$ )

					-40°C to	o +85°C					
					V <sub>CCI</sub>	<sub>B</sub> (V)					
	4.	.5	3	.3	2.	.8	1.	.8	0.	.9	
V <sub>CCA</sub> (V)	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
4.5		2		2		2		2		< 1.5	μΑ
3.3		2		2		2		2		< 1.5	μΑ
2.8		< 2		< 1		< 1		< 0.5		< 0.5	μΑ
1.8		< 1		< 1		< 0.5		< 0.5		< 0.5	μΑ
0.9		< 0.5		< 0.5		< 0.5		< 0.5		< 0.5	μΑ

NOTE: Connect ground before applying supply voltage V<sub>CCA</sub> or V<sub>CCB</sub>. This device is designed with the feature that the power–up sequence of V<sub>CCA</sub> and V<sub>CCB</sub> will not damage the IC.

# **AC ELECTRICAL CHARACTERISTICS**

							-40°C t	o +85°C					
							V <sub>CC</sub>	<sub>B</sub> (V)					
			4.	.5	3	.3	2	.8	1	.8	1.	.2	
Symbol	Parameter	V <sub>CCA</sub> (V)	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
t <sub>PLH</sub> ,	Propagation	4.5		1.6		1.8		2.0		2.1		2.3	nS
t <sub>PHL</sub> (Note 1)	Delay,	3.3		1.7		1.9		2.1		2.3		2.6	
(Note 1)	A <sub>n</sub> to B <sub>n</sub>	2.8		1.9		2.1		2.3		2.5		2.8	
		1.8		2.1		2.4		2.5		2.7		3.0	
		1.2		2.4		2.7		2.8		3.0		3.3	
t <sub>PZH</sub> ,	Output	4.5		2.6		3.8		4.0		4.1		4.3	nS
t <sub>PZL</sub> (Note 1)	Enable,	3.3		3.7		3.9		4.1		4.3		4.6	
(Note 1)	OE to B <sub>n</sub>	2.5		3.9		4.1		4.3		4.5		4.8	
		1.8		4.1		4.4		4.5		4.7		5.0	
		1.2		4.4		4.7		4.8		5.0		5.3	
t <sub>PHZ</sub> ,	Output	4.5		2.6		3.8		4.0		4.1		4.3	nS
t <sub>PLZ</sub>	Disable,	3.3		3.7		3.9		4.1		4.3		4.6	
(Note 1)	OE to B <sub>n</sub>	2.5		3.9		4.1		4.3		4.5		4.8	
		1.8		4.1		4.4		4.5		4.7		5.0	
		1.2		4.4		4.7		4.8		5.0		5.3	
t <sub>OSHL</sub> ,	Output to	4.5		0.15		0.15		0.15		0.15		0.15	nS
toslh	Output Skew,	3.3		0.15		0.15		0.15		0.15		0.15	
(Note 1)	Time	2.5		0.15		0.15		0.15		0.15		0.15	
		1.8		0.15		0.15		0.15		0.15		0.15	
		1.2		0.15		0.15		0.15		0.15		0.15	

<sup>1.</sup> Propagation delays defined per Figure 2.

# **CAPACITANCE**

Symbol	Parameter	Test Conditions	Typ (Note 2)	Unit
C <sub>IN</sub>	Control Pin Input Capacitance	$V_{CCA} = V_{CCB} = 3.3 \text{ V}, V_I = 0 \text{ V or } V_{CCA/B}$	3.5	pF
C <sub>I/O</sub>	I/O Pin Input Capacitance	$V_{CCA} = V_{CCB} = 3.3 \text{ V}, V_I = 0 \text{ V or } V_{CCA/B}$	5.0	pF
C <sub>PD</sub>	Power Dissipation Capacitance	$V_{CCA} = V_{CCB} = 3.3 \text{ V}, V_I = 0 \text{ V or } V_{CCA}, f = 10 \text{ MHz}$	20	pF

Typical values are at T<sub>A</sub> = +25°C.
 C<sub>PD</sub> is defined as the value of the IC's equivalent capacitance from which the operating current can be calculated from: I<sub>CC(operating)</sub> ≅ C<sub>PD</sub> x V<sub>CC</sub> x f<sub>IN</sub> x N<sub>SW</sub> where I<sub>CC</sub> = I<sub>CCA</sub> + I<sub>CCB</sub> and N<sub>SW</sub> = total number of outputs switching.

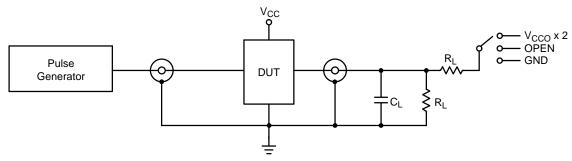


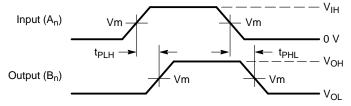
Figure 2. AC (Propagation Delay) Test Circuit

Test	Switch
t <sub>PLH</sub> , t <sub>PHL</sub>	OPEN
t <sub>PLZ</sub> , t <sub>PZL</sub>	V <sub>CCO</sub> x 2
t <sub>PHZ</sub> , t <sub>PZH</sub>	GND

C<sub>L</sub> = 15 pF or equivalent (includes probe and jig capacitance)

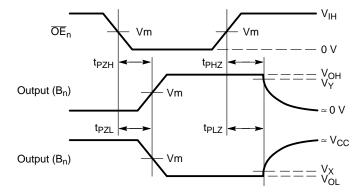
 $R_L = 2 k\Omega$  or equivalent

 $Z_{OUT}$  of pulse generator = 50  $\Omega$ 



# Waveform 1 – Propagation Delays

 $t_R = t_F = 2.0 \text{ ns}, 10\% \text{ to } 90\%; f = 1 \text{ MHz}; t_W = 500 \text{ ns}$ 



#### Waveform 2 - Output Enable and Disable Times

 $t_R = t_F = 2.0 \text{ ns}, 10\% \text{ to } 90\%; f = 1 \text{ MHz}; t_W = 500 \text{ ns}$ 

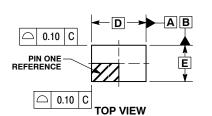
Figure 3. AC (Propagation Delay) Test Circuit Waveforms

		V <sub>CC</sub>						
Symbol	3.0 V – 4.5 V	2.3 V – 2.7 V	1.65 V – 1.95 V	1.4 V – 1.6 V	0.9 V – 1.3 V			
$V_{mA}$	V <sub>CCA</sub> /2							
V <sub>mB</sub>	V <sub>CCB</sub> /2							
V <sub>X</sub>	V <sub>OL</sub> x 0.1							
V <sub>Y</sub>	V <sub>OH</sub> x 0.9							

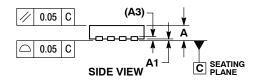
SCALE 4:1

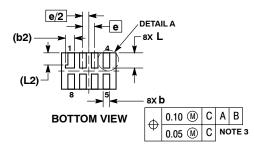


**DATE 08 NOV 2006** 

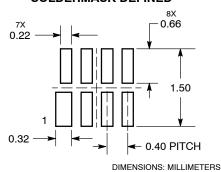








### **MOUNTING FOOTPRINT SOLDERMASK DEFINED**



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
  CONTROLLING DIMENSION: MILLIMETERS.
  DIMENSION & APPLIES TO PLATED
- DINICIPION D APPLIES TO PLATED
  TERMINAL AND IS MEASURED BETWEEN
  0.15 AND 0.30 mm FROM TERMINAL TIP.
  MOLD FLASH ALLOWED ON TERMINALS
  ALONG EDGE OF PACKAGE, FLASH MAY
  NOT EXCEED 0.03 ONTO BOTTOM
  SURFACE OF TERMINALS.
  DETAIL A SHOWS ODTIONAL
- DETAIL A SHOWS OPTIONAL CONSTRUCTION FOR TERMINALS.

	<b>MILLIMETERS</b>						
DIM	MIN	MAX					
Α	0.45	0.55					
A1	0.00	0.05					
A3	0.127	REF					
b	0.15	0.25					
b2	0.30	REF					
D	1.80	BSC					
E	1.20	BSC					
е	0.40	BSC					
L	0.45	0.55					
L1	0.00	0.03					
L2	0.40	REF					

# **GENERIC MARKING DIAGRAM\***



XX = Specific Device Code

= Date Code

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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DESCRIPTION:	UDFN8 1.8X1.2. 0.4P	•	PAGE 1 OF 1

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SOIC-8 NB CASE 751-07 **ISSUE AK** 

**DATE 16 FEB 2011** 



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982. CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		MILLIMETERS INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
Н	0.10	0.25	0.004	0.010
J	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
М	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

# **SOLDERING FOOTPRINT\***



<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

# **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code = Assembly Location

= Wafer Lot = Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

#### **STYLES ON PAGE 2**

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DESCRIPTION:	SOIC-8 NB		PAGE 1 OF 2

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# SOIC-8 NB CASE 751-07 ISSUE AK

# DATE 16 FEB 2011

STYLE 3: PIN 1. DRAIN, PIE #1 CTOR, #1 CTOR, #2 CTOR, #1 CTOR, #2 CTOR, #2 CTOR, #2 CTOR, #2 CTOR, #1	2. ANODE 3. ANODE 4. ANODE 5. ANODE 6. ANODE 7. ANODE 8. COMMON CATHODE  STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #1 Vd  STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN 8. TYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #1
E PIN 1. INPUT 2. EXTERNAL BY 3. THIRD STAGE 4. GROUND E 5. DRAIN 6. GATE 3 7. SECOND STAGE 8. FIRST STAGE STYLE 11: ID PIN 1. SOURCE 1 2. GATE 1 T 3. SOURCE 2 ID 4. GATE 2 ID 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 ID 8. DRAIN 1 ID	PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 Vd 8. COLLECTOR, #1  STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN 8. TYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
ID PIN 1. SOURCE 1 2. GATE 1 T 3. SOURCE 2 ID 4. GATE 2 ID 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 ID 8. DRAIN 1 STYLE 15: RCE PIN 1. ANODE 1 E 2. ANODE 1 RCE 3. ANODE 1	PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
STYLE 15:  RCE PIN 1. ANODE 1 E 2. ANODE 1 RCE 3. ANODE 1	PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2
N 7. CATHODE, CON N 8. CATHODE, CON	MMON         5. COLLECTOR, DIE #2           MMON         6. COLLECTOR, DIE #2           MMON         7. COLLECTOR, DIE #1           MMON         8. COLLECTOR, DIE #1
STYLE 19: PIN 1. SOURCE 1 E 2. GATE 1 E 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 DE 7. DRAIN 1 DE 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 23: E1 PIN 1. LINE 1 IN DN CATHODE/VCC 2. COMMON ANC DN CATHODE/VCC 3. COMMON ANC E3 4. LINE 2 IN DN ANODE/GND 5. LINE 2 OUT E4 6. COMMON ANC E5 7. COMMON ANC DN ANODE/GND 8. LINE 1 OUT	ODE/GND 2. EMITTER ODE/GND 3. COLLECTOR/ANODE
STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V MON 6. VBULK 7. VBULK 8. VIN
1 1	
;	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ E 5. SOURCE E 6. SOURCE E 7. SOURCE 8. DRAIN

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#### Micro8 CASE 846A-02 ISSUE K

**DATE 16 JUL 2020** 









#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.10 mm IN EXCESS OF MAXIMUM MATERIAL CONDITION.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 mm PER SIDE. DIMENSION E DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 mm PER SIDE. DIMENSIONS D AND E ARE DETERMINED AT DATUM F.
- DATUMS A AND B ARE TO BE DETERMINED AT DATUM F.
- A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.



MOUNTING FOOTPRINT

DIM	MI	LLIMETE	RS
DIM	MIN.	N□M.	MAX.
Α	-	-	1.10
A1	0.05	0.08	0.15
b	0.25	0.33	0.40
c	0.13	0.18	0.23
D	2.90	3.00	3.10
Ε	2.90	3.00	3.10
е	0.65 BSC		
HE	4.75	4.90	5.05
L	0.40	0.55	0.70

# **GENERIC MARKING DIAGRAM\***



XXXX = Specific Device Code Α = Assembly Location

Υ = Year W = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLE 1:	STYLE 2:	STYLE 3:
PIN 1. SOURCE	PIN 1. SOURCE 1	PIN 1. N-SOURCE
<ol><li>SOURCE</li></ol>	2. GATE 1	2. N-GATE
<ol><li>SOURCE</li></ol>	3. SOURCE 2	3. P-SOURCE
<ol><li>GATE</li></ol>	4. GATE 2	4. P-GATE
<ol><li>DRAIN</li></ol>	5. DRAIN 2	5. P-DRAIN
<ol><li>DRAIN</li></ol>	6. DRAIN 2	6. P-DRAIN
7. DRAIN	7. DRAIN 1	7. N-DRAIN
8. DRAIN	8. DRAIN 1	8. N-DRAIN

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